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L1	11	richard-Taylor.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:12
L2	0	monitierth-melvin.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:11
L3	10	zimmerman-gary.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:32
L4	3728	((volatile adj2 memor\$3) or RAM or DRAM) near3 check\$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:35
L5	58	((volatile adj2 memor\$3) or RAM or DRAM) near3 checker	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:35
L7	152	((volatile adj2 memor\$3) or RAM or DRAM) and (detect\$4 near3 (soft adj2 error\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:38
L8	45	(((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (detect\$4 near3 (soft adj2 error\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:39
L10	12	(((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (detect\$4 near3 (soft adj2 error\$1)) and (timer)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:40
L11	8	(((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (detect\$4 near3 (soft adj2 error\$1)) and (timer) and test\$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:53
L12	0	(((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (detect\$4 near3 (soft adj2 error\$1)) and (timer) and (test\$4 near3 code\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:40
L13	4	(((volatile adj2 memor\$3) or RAM or DRAM or memory)) and (detect\$4 near3 (soft adj2 error\$1)) and (timer) and (test\$4 near3 code\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:42
L14	6	(((volatile adj2 memor\$3) or RAM or DRAM or memory)) and (detect\$4 near3 (soft adj2 error\$1)) and (test\$4 near3 code\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:45

L15	31	((volatile adj2 memor\$3) or RAM or DRAM or memory)) and (detect\$4 near3 (soft adj2 error\$1)) and (self near3 test\$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:46
L16	73	((volatile adj2 memor\$3) or RAM or DRAM or memory)) and ((self near3 test\$4) or (self-tester)) and (recovery adj3 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:48
L17	3	((volatile adj2 memor\$3) or RAM or DRAM or memory)) and (((self near3 test\$4) or (self-tester)) near15 detect\$4) and (recovery adj3 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:52
L18	15	((volatile adj2 memor\$3) or RAM or DRAM or memory) near5 checker) and (((self near3 test\$4) or (self-tester)) near15 detect\$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:51
L19	5	((volatile adj2 memor\$3) or RAM or DRAM or memory)) and (((self near3 test\$4) or (self-tester)) near15 detect\$4) and (recov\$4 near3 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:14
L20	11	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) same (detect\$4 near3 (soft adj2 error\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:53
L21	0	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) same (detect\$4 near3 (soft adj2 error\$1))) and CRC	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:53
L22	0	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) same (detect\$4 near3 (soft adj2 error\$1))) and (CRC or checksum\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:54
L24	896	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (printer near3 control\$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:55
L25	219	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (printer adj2 controller)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:56
L26	210	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (printer adj2 controller) and process\$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:56
L27	129	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (printer adj2 controller) and processor	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:56

L28	1	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3 and (printer adj2 controller) and processor and (recovery near2 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:57
L29	7	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3 and (printer adj2 controller) and (recovery near2 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:57
L30	114	((volatile adj2 memor\$3) or RAM or DRAM or SRAM or memory) and ((self near3 test\$4) or self-test\$3) and (recov\$4 near3 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:16
L31	14	((volatile adj2 memor\$3) or RAM or DRAM or SRAM or memory) and (((self near3 test\$4) or self-test\$3) same (recov\$4 near3 module\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:16
L32	13	((volatile adj2 memor\$3) or RAM or DRAM or SRAM or memory) and (((self near3 test\$4) or self-test\$3) same (recov\$4 near3 module\$1)) and (detect\$4 or check\$3 or CRC or checksum\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:17
L33	13	((volatile adj2 memor\$3) or RAM or DRAM or SRAM or memory) and (((self near3 test\$4) or self-test\$3) same (recov\$4 near3 module\$1)) and (detect\$4 or check\$3 or CRC or checksum\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:17

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Oldfield, M.K.; Underwood, C.I.;

Nuclear Science, IEEE Transactions on

Volume 43, Issue 6, Dec. 1996 Page(s):2715 - 2723

[AbstractPlus](#) | Full Text: [PDF\(780 KB\)](#) [IEEE JNL](#)**2. A flexible analog memory address list manager for PHENIX**

Ericson, M.N.; Musrock, M.S.; Britton, C.L., Jr.; Walker, J.W.; Winterberg, A.L.; Young, Nuclear Science, IEEE Transactions on Volume 43, Issue 3, June 1996 Page(s):1629 - 1633

[AbstractPlus](#) | Full Text: [PDF\(452 KB\)](#) [IEEE JNL](#)**3. A 1006 element hybrid silicon pixel detector with strobed binary output**

Anghinolfi, F.; Aspell, P.; Bass, K.; Beusch, W.; Bosisio, L.; Boutonnet, C.; Burger, P.; Chesi, E.; Claeys, C.; Clemens, J.C.; Cohen Solal, M.; Debusschere, I.; Delpierre, P.; Dierickx, B.; Enz, C.C.; Focardi, E.; Forti, F.; Gally, Y.; Glaser, M.; Gys, T.; Habrard, M. E.H.M.; Hermans, L.; Hurst, R.; Inzani, P.; Jaeger, J.J.; Jarron, P.; Krummenacher, F.; Lenti, V.; Manzari, V.; Meddeler, G.; Morando, M.; Munns, A.; Nava, F.; Navach, F.; Ne G.; Pellegrini, F.; Pengg, F.; Perego, R.; Pindo, M.; Potheau, R.; Quercigh, E.; Redaelli Sauvage, D.; Segato, G.; Simone, S.; Stefanini, G.; Tonelli, G.; Vanstraelen, G.; Vigni, Viertel, G.M.; Waisbard, J.;

Nuclear Science, IEEE Transactions on

Volume 39, Issue 4, Aug 1992 Page(s):654 - 661

[AbstractPlus](#) | Full Text: [PDF\(992 KB\)](#) [IEEE JNL](#)**4. Results of radiation tests performed on the ISOCAM infrared detector array**

Agnese, P.; Engelmann, J.J.; Mottier, P.;

Nuclear Science, IEEE Transactions on

Volume 38, Issue 4, Aug. 1991 Page(s):953 - 963

[AbstractPlus](#) | Full Text: [PDF\(704 KB\)](#) [IEEE JNL](#)**5. Performance of the electronics for the liquid argon calorimeter system of the SLC**

Vella, E.; Abt, I.; Haller, G.M.; Honma, A.;

Nuclear Science, IEEE Transactions on

Volume 36, Issue 1, Feb. 1989 Page(s):822 - 825

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- 6. Comparison of known signal detection schemes under a weakly dependent noise Kim, T.; Yun, J.S.; Song, I.; Na, Y.J.; Vision, Image and Signal Processing, IEE Proceedings- Volume 141, Issue 5, Oct. 1994 Page(s):303 - 310
[AbstractPlus](#) | Full Text: [PDF\(432 KB\)](#) IEE JNL
- 7. Reducing power consumption in memory ECC checkers Ghosh, S.; Basu, S.; Touba, N.A.; Test Conference, 2004. Proceedings. International 2004 Page(s):1322 - 1331
[AbstractPlus](#) | Full Text: [PDF\(937 KB\)](#) IEEE CNF
- 8. Asymptotic performance comparison of known signal detection schemes in weak noise Taehyun Kim; Jin Seon Yun; Sun Yong Kim; Ickho Song; Military Communications Conference, 1994. MILCOM '94. Conference Record, 1994 IE 2-5 Oct. 1994 Page(s):276 - 280 vol.1
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- 9. Finite sample-size performance of known signal detectors in a weakly dependent noise Taehyun Kim; Jill Seon Yun; Young Kwon Ryu; Ickho Song; Electrical and Computer Engineering, 1994. Conference Proceedings. 1994 Canadian 25-28 Sept. 1994 Page(s):288 - 291 vol.1
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- 10. A flexible analog memory address list manager for PHENIX Ericson, M.N.; Musrock, M.S.; Britton, C.L., Jr.; Walker, J.W.; Wintenberg, A.L.; Young, M.D.; Nuclear Science Symposium and Medical Imaging Conference Record, 1995., 1995 IE Volume 1, 21-28 Oct. 1995 Page(s):5 - 9 vol.1
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Hatanaka, M.; Miyoshi, H.; Yoshihara, T.;
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- 13. Word-level symbolic simulation in processor verification**
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- 14. Detecting faults in the peripheral circuits and an evaluation of SRAM tests**
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- 16. **SafeMem: Exploiting ECC-Memory for Detecting Memory Leaks and Memory Corruption in Production Runs**
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- 17. **Detection of control flow errors using signature and checking instructions**
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- 19. **On reducing test time and meeting deadlines in real-time systems**
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- 22. **Experimental evaluation of the fail-silent behaviour in programs with consistency constraints**
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- 23. **Dynamic test compaction for synchronous sequential circuits using static compaction techniques**
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- 24. **Achieving fault secureness In parity prediction arithmetic operators: general concepts and implementations**
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